## Application/Control No. Applicant(s)/Patent Under Reexamination CHILDS ET AL. Examiner Thu Nguyen Applicant(s)/Patent Under Reexamination CHILDS ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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## **FOREIGN PATENT DOCUMENTS**

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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Shiau (US 2002/0091527 A1) class 704/270.1
	٧	Levanon et al (US 2002/0120753 A1) class 709/228
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